

Search Notes**Application/Control No.**

10/710,456

Examiner

Huyen Le

**Applicant(s)/Patent under
Reexamination**

KEMP ET AL.

Art Unit

3751

SEARCHED

Class	Subclass	Date	Examiner
4	576.1 577.1	6/6/2008	HL
	Updated		

INTERFERENCE SEARCHED

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US-PGPUB		6/9/2008	HL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR